

<b>Notice of References Cited</b>	Application/Control No. 10/501,315		Applicant(s)/Patent Under Reexamination TO, BAN CHIN	
	Examiner David J. Makiya		Art Unit 2885	Page 1 of 1

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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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